

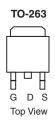
IXTA80N10T-VB Datasheet N-Channel 100-V (D-S) MOSFET

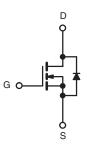
PRODUCT SUMMARY					
V _{DS} (V)	$R_{DS(on)}(\Omega)$	I _D (A)			
100	0.010 at V _{GS} = 10 V	100			
	0.023 at $V_{GS} = 4.5 \text{ V}$	85			

FEATURES

- Trench Power MOSFET
- 175 °C Maximum Junction Temperature
- · Compliant to RoHS Directive 2002/95/EC







N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS T _A = 25 °C, unless otherwise noted						
Parameter			Limit	Unit		
Drain-Source Voltage			100	V		
Gate-Source Voltage			± 20	V		
Continuous Drain Current (T _J = 150 °C)	T _C = 25 °C	I_	100			
	T _C = 125 °C	I _D	75 ^a			
Pulsed Drain Current	I _{DM}	300	Α			
Avalanche Current	L = 0.1 mH	I _{AS}	75			
Single Pulse Avalanche Energy ^b	L = 0.1 IIII I	E _{AS}	280	mJ		
Mariana Barra Birainati alb	T _C = 25 °C (TO-220AB and TO-263)	P _D	250 ^c	W		
Maximum Power Dissipation ^b	T _A = 25 °C (TO-263) ^d	٠ ٥	3.75]		
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to 175	°C		

THERMAL RESISTANCE RATINGS					
Parameter		Symbol	Limit	Unit	
Junction-to-Ambient	PCB Mount (TO-263) ^d	- R _{thJA}	40	°C/W	
Junction-to-Ambient	Free Air (TO-220AB)	' 'thJA	62.5		
Junction-to-Case		R _{thJC}	0.6		

Notes:

- a. Pulse test; pulse width \leq 300 μ s, duty cycle \leq 2 %.
- b. Guaranteed by design, not subject to production testing.
- c. Independent of operating temperature.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.



Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit
Static			•			
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	100			
Gate-Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_D = 250 \mu A$	2		4	V
Gate-Body Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA
		V _{DS} = 100 V, V _{GS} = 0 V			1	
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 100 V, V _{GS} = 0 V, T _J = 125 °C			50	μΑ
		V _{DS} = 100 V, V _{GS} = 0 V, T _J = 175 °C			250	
On-State Drain Current ^a	I _{D(on)}	$V_{DS} = \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	120			Α
		$V_{GS} = 10 \text{ V}, I_D = 30 \text{ A}$		0.010		<u>† </u>
	B	$V{GS} = 4.5 \text{ V}, I_D = 20 \text{ A}$		0.023		0
Drain-Source On-State Resistance ^a	H _{DS(on)}	V _{GS} = 10 V, I _D = 30 A, T _J = 125 °C		0.020		Ω
		V _{GS} = 10 V, I _D = 30 A, T _J = 175 °C		0.030		
Forward Transconductance ^a	9 _{fs}	$V_{DS} = 15 \text{ V}, I_{D} = 30 \text{ A}$	25			S
Dynamic ^b						
Input Capacitance	C _{iss}			6550		pF
Output Capacitance	C _{oss}	$V_{GS} = 0 \text{ V}, V_{DS} = 25 \text{ V}, f = 1 \text{ MHz}$		665		
Reverse Transfer Capacitance	C _{rss}]		265		
Total Gate Charge ^c	Q_g			105	160	
Gate-Source Charge ^c	Q _{gs}	$V_{DS} = 50 \text{ V}, V_{GS} = 10 \text{ V}, I_{D} = 85 \text{ A}$		17		nC
Gate-Drain Charge ^c	Q_{gd}	7		23		
Turn-On Delay Time ^c	t _{d(on)}			12	25	
Rise Time ^c	t _r	$V_{DD} = 50 \text{ V}, R_{L} = 0.6 \Omega$		90	135	
Turn-Off DelayTime ^c	t _{d(off)}	$I_D\cong 85~A,~V_{GEN}=10~V,~R_g=2.5~\Omega$		55	85	ns
Fall Time ^c	t _f	7		130	195	
Source-Drain Diode Ratings and Cha	acteristics T _C	= 25 °C ^b				
Continuous Current	I _S				85	Λ
Pulsed Current	I _{SM}				240	Α
Forward Voltage ^a	V _{SD}	I _F = 85 A, V _{GS} = 0 V		1.0	1.5	V
Reverse Recovery Time	t _{rr}			85	140	ns
Peak Reverse Recovery Current	I _{RM(REC)}	I _F = 50 A, dI/dt = 100 A/μs		4.5	7	Α
Reverse Recovery Charge	Q _{rr}	1		0.17	0.35	μC

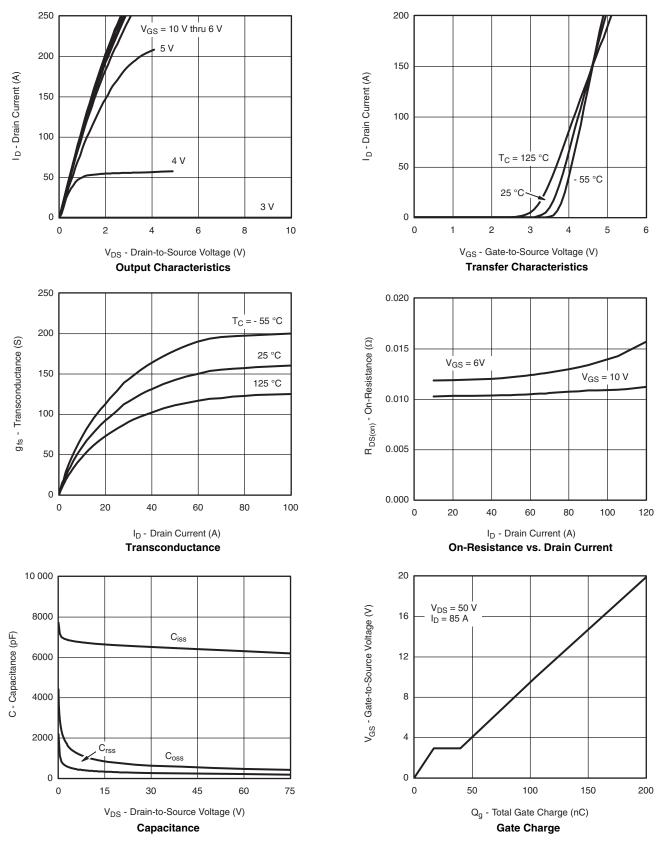
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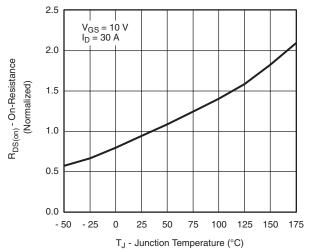
TYPICAL CHARACTERISTICS $T_A = 25 \, ^{\circ}C$, unless otherwise noted



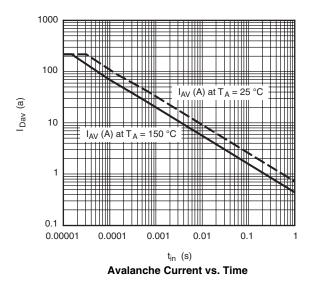
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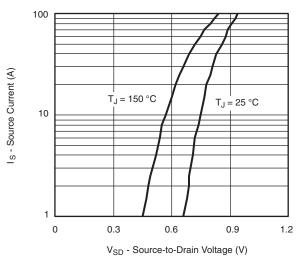


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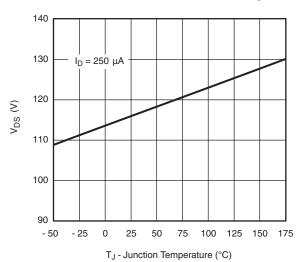


On-Resistance vs. Junction Temperature





Source-Drain Diode Forward Voltage

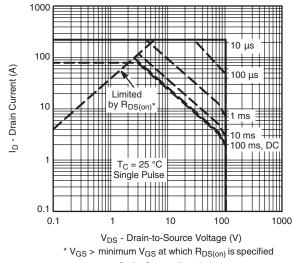


T_J - Drain-Source Breakdown vs. Junction-Temperature

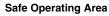


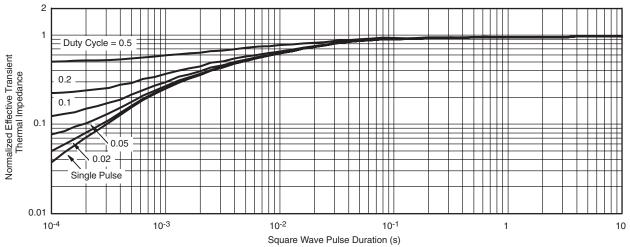
THERMAL RATINGS





Maximum Avalanche and Drain Current vs. Case Temperature



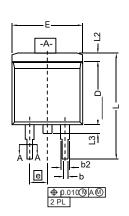


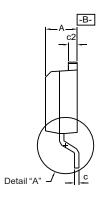
Normalized Thermal Transient Impedance, Junction-to-Case

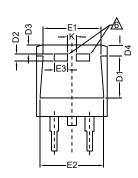


MILLIMETERS

TO-263 (D²PAK): 3-LEAD







INCHES



DETAIL A (ROTATED 90°)

5.	b b1 ↓	<u> </u>
_	5	ပ
	SECTION A-A	1

Notes

- 1. Plane B includes maximum features of heat sink tab and plastic.
- 2. No more than 25 % of L1 can fall above seating plane by $\;$ max. 8 mils.
- 3. Pin-to-pin coplanarity max. 4 mils.
- 4. *: Thin lead is for SUB, SYB.
 Thick lead is for SUM, SYM, SQM.
- 5. Use inches as the primary measurement.

 This feature is for thick lead.

DIM.		MIN.	MAX.	MIN.	MAX.	
Α		0.160	0.190	4.064	4.826	
b		0.020	0.039	0.508	0.990	
	b1	0.020	0.035	0.508	0.889	
b2		0.045	0.055	1.143	1.397	
С*	Thin lead	0.013	0.018	0.330	0.457	
	Thick lead	0.023	0.028	0.584	0.711	
-4	Thin lead	0.013	0.017	0.330	0.431	
c1	Thick lead	0.023	0.027	0.584	0.685	
	c2	0.045	0.055	1.143	1.397	
	D	0.340	0.380	8.636	9.652	
D1		0.220	0.240	5.588	6.096	
D2		0.038	0.042	0.965	1.067	
D3		0.045	0.055	1.143	1.397	
D4		0.044	0.052	1.118	1.321	
E		0.380	0.410	9.652	10.414	
E1		0.245	-	6.223	-	
E2		0.355	0.375	9.017	9.525	
E3		0.072	0.078	1.829	1.981	
е		0.100	BSC	2.54 BSC		
K		0.045	0.055	1.143	1.397	
L		0.575	0.625	14.605	15.875	
L1		0.090	0.110	2.286	2.794	
L2		0.040	0.055	1.016	1.397	
L3		0.050	0.070	1.270	1.778	
L4		0.010	0.010 BSC		0.254 BSC	
	М	-	0.002	-	0.050	
FCN: T13-0707-Rev. K. 30-Sep-13						

ECN: T13-0707-Rev. K, 30-Sep-13

DWG: 5843



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